

Search Notes

Application/Control No.

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EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

YAMAKAWA ET AL.

Art Unit

1732

SEARCHED

Class	Subclass	Date	Examiner
updated		12/26/2006	EHL

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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